

**Search Notes**

Application/Control No.

10/790,149

Examiner

Y Quach Lee

Applicant(s)/Patent under  
Reexamination

CHEN, JINZU

Art Unit

2875

**SEARCHED**

Class	Subclass	Date	Examiner
362	561 630 631 632 633 634 609 611 612 613	6/30/2005	YMY
	614		
349	58 60		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
NONE	6/30/2005	YMY